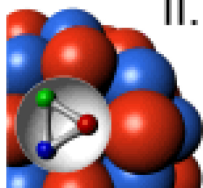


The PASTA chip for the silicon micro strip sensor of the PANDA MVD

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- 3) INFN Sezione di Torino



II. Physikalisches
Institut

DPG Spring Meeting 2016

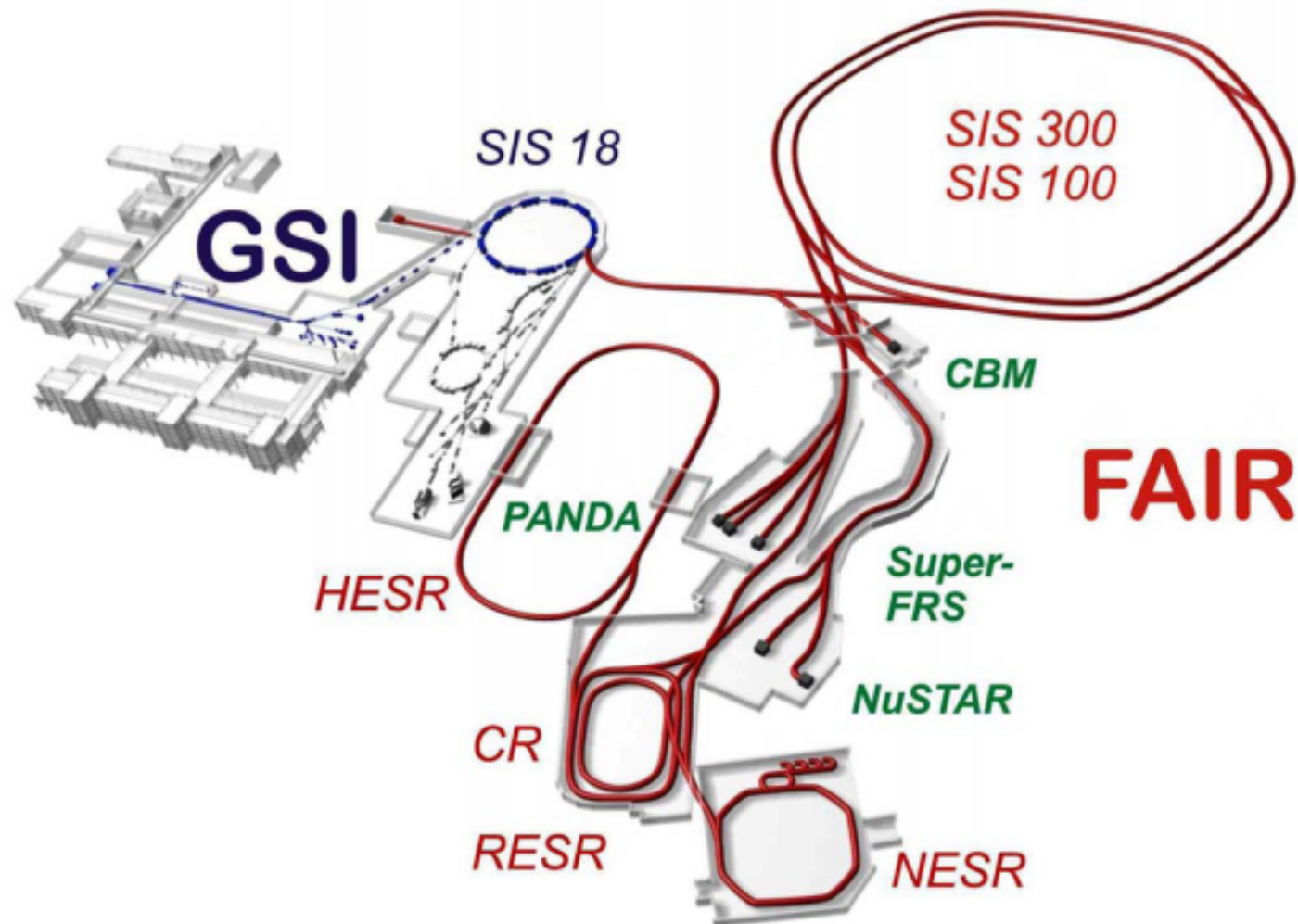


Contents

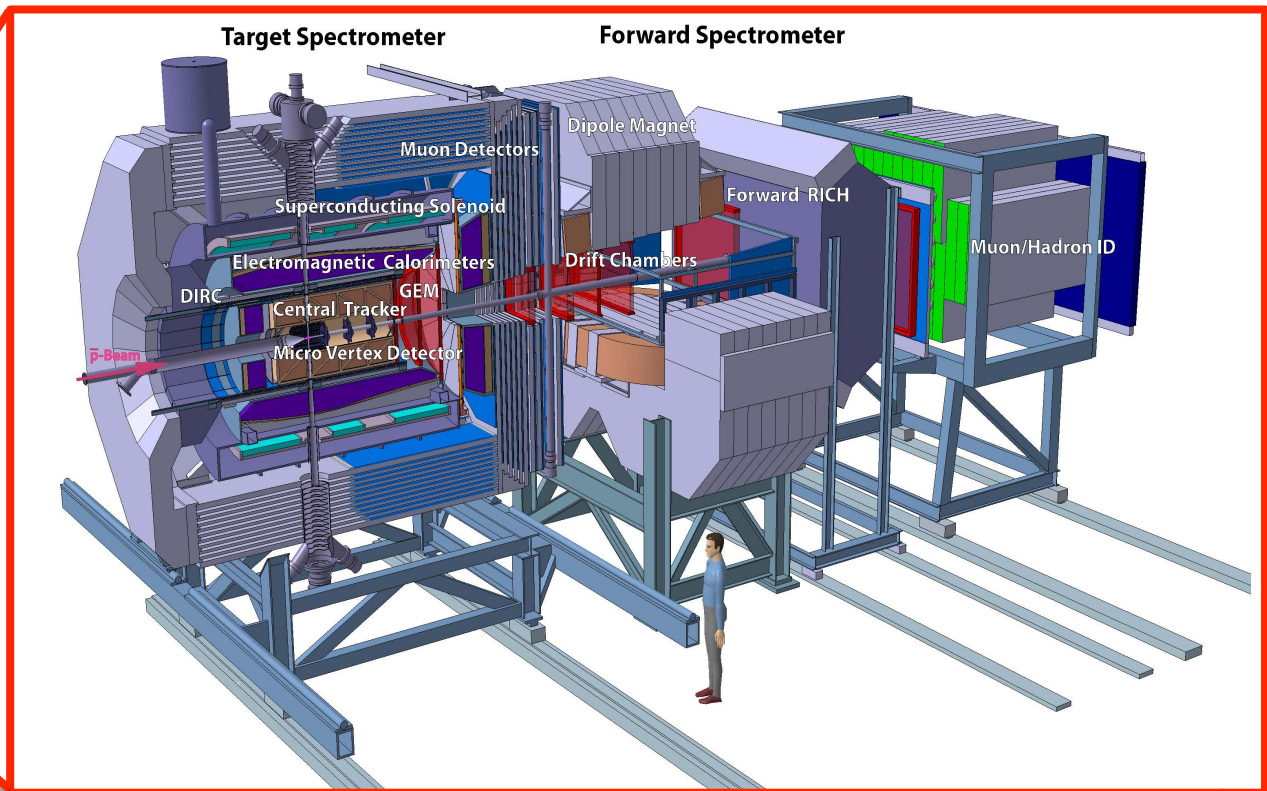
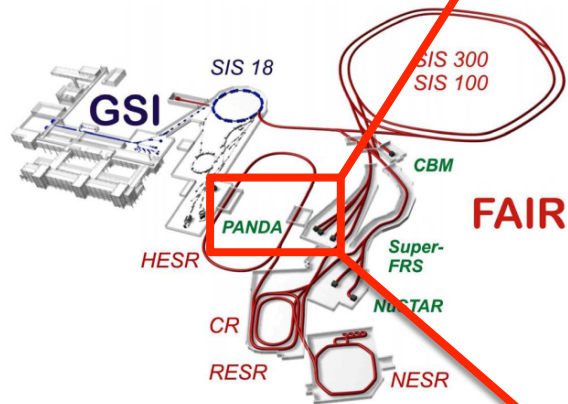


1. Context
2. ASIC design
3. Current status
4. Outlook

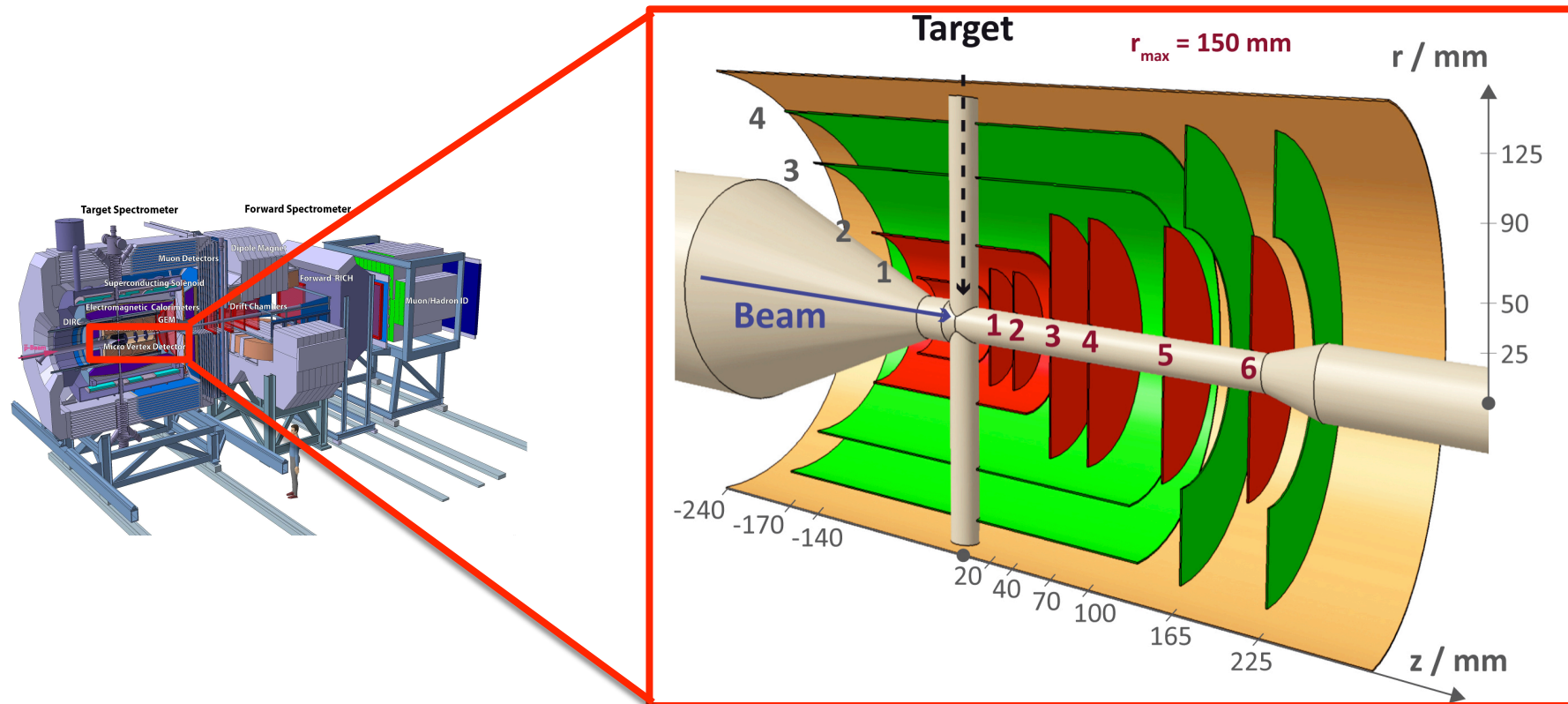
FAIR



PANDA



MicroVertex Detector



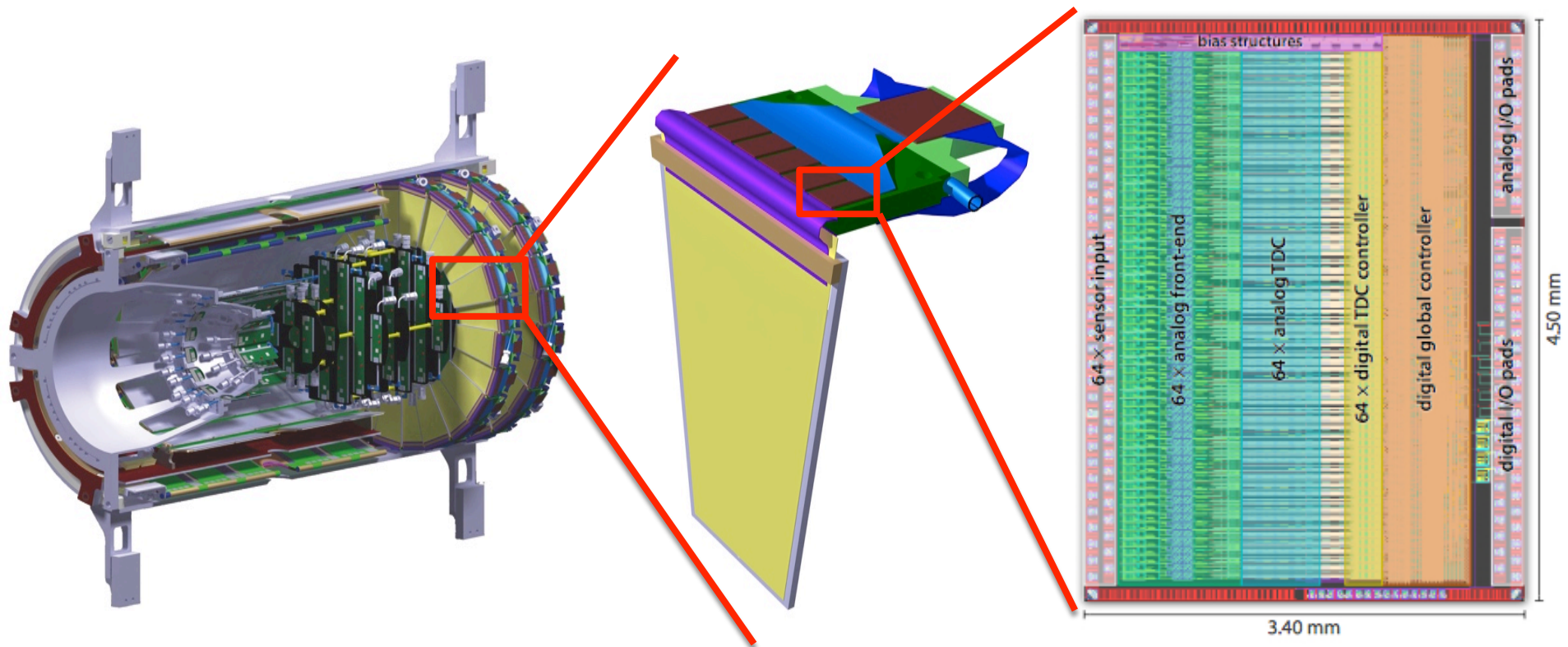
Red zone covered by pixels and green one by strips

PAnda STrip Asic (PASTA)

Micro Vertex Detector

Sensor Module

Readout ASIC



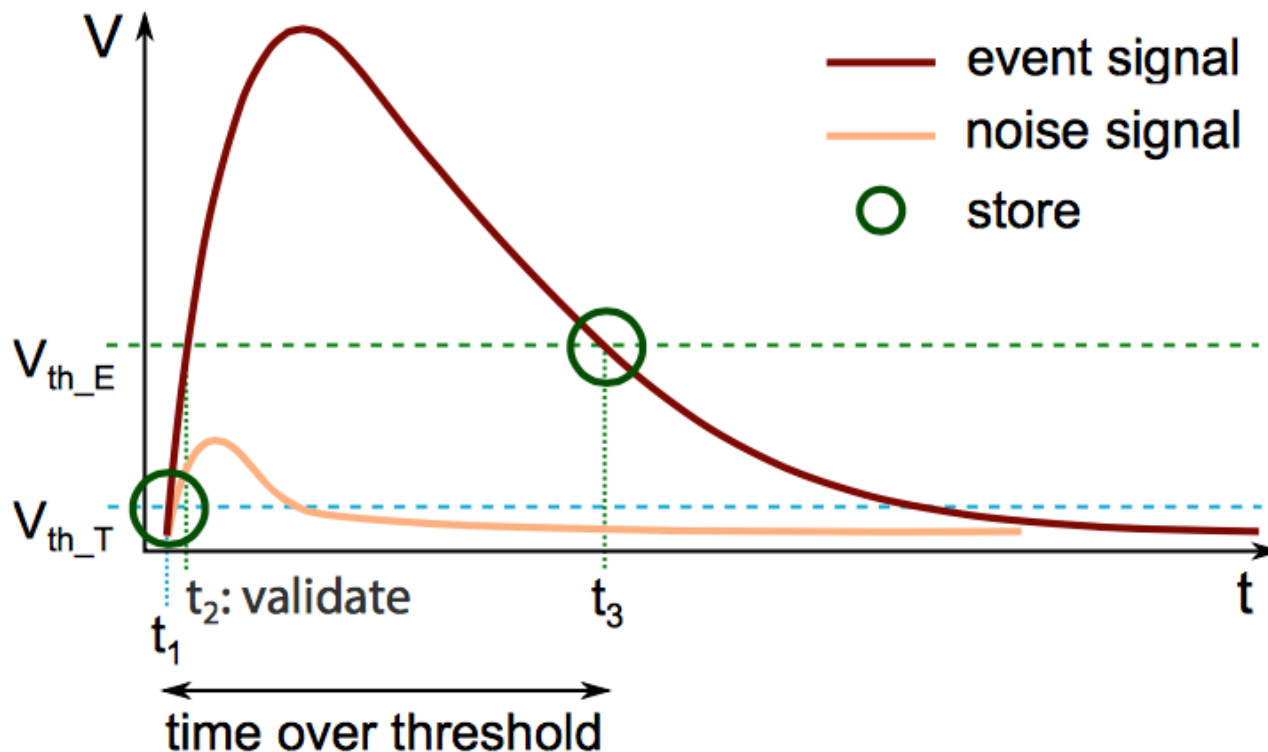
PASTA Features



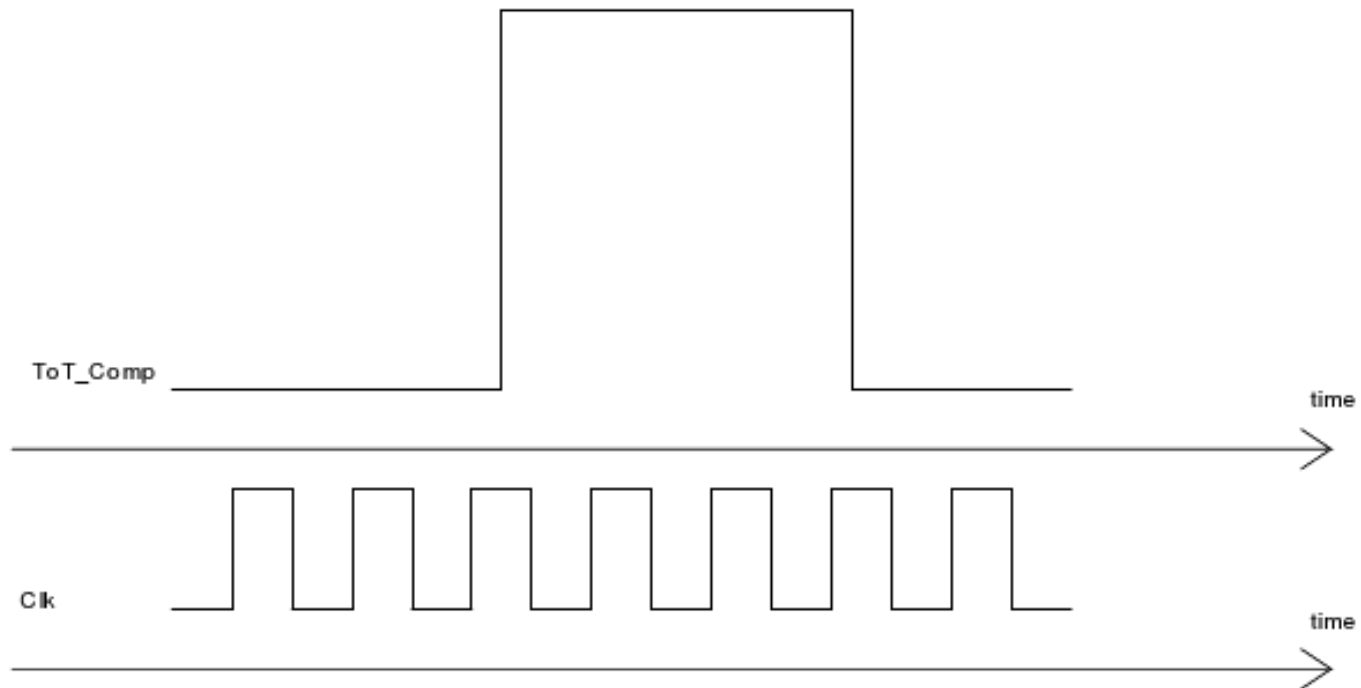
- 64 Channels
- 63 μm input pitch
- 100 kHz Rate/channel
- Less than 4 mW per channel
- Triggerless
- Radiation tolerance 100 kGy

Measurement Concept

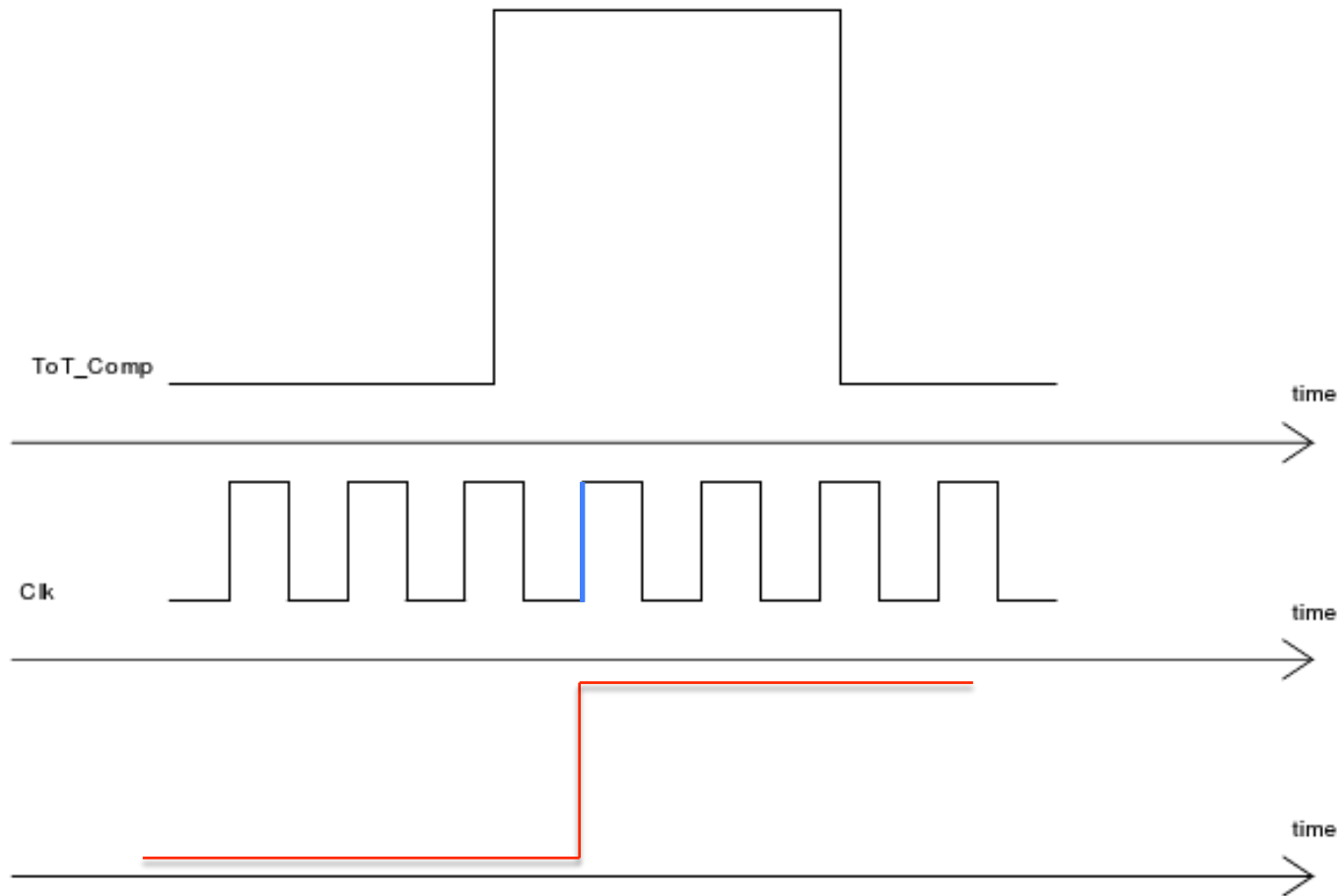
- Low threshold: better time stamp resolution
- High threshold: better jitter performance



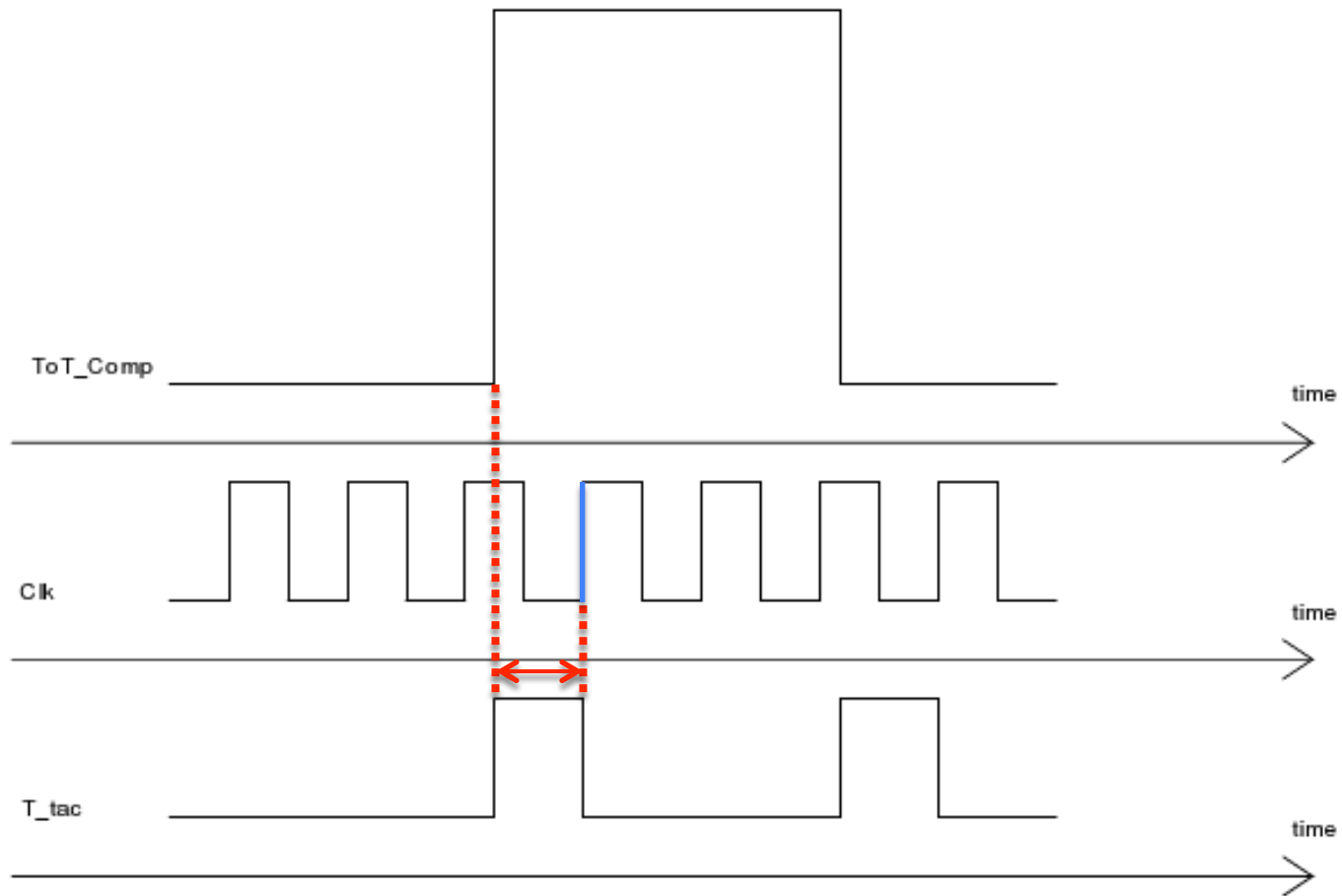
Timing



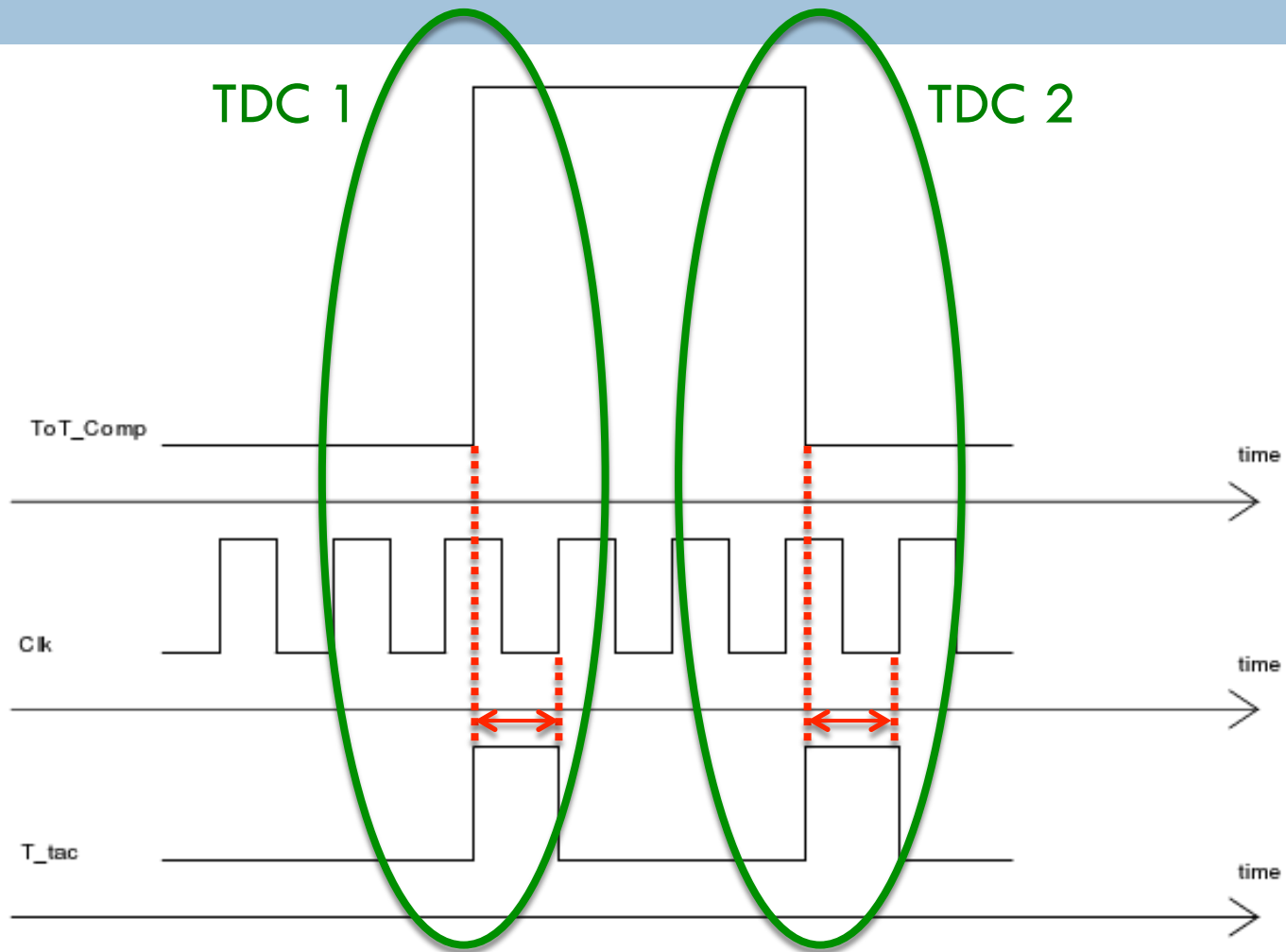
Timing



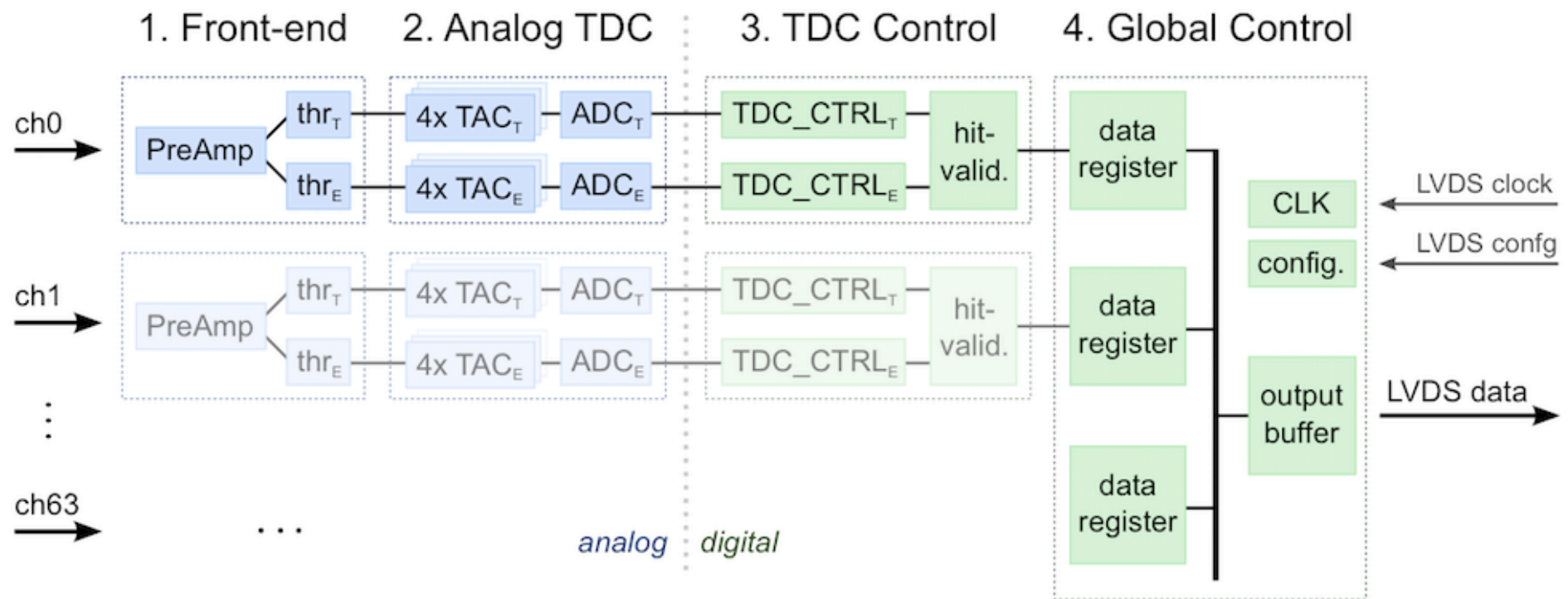
Timing



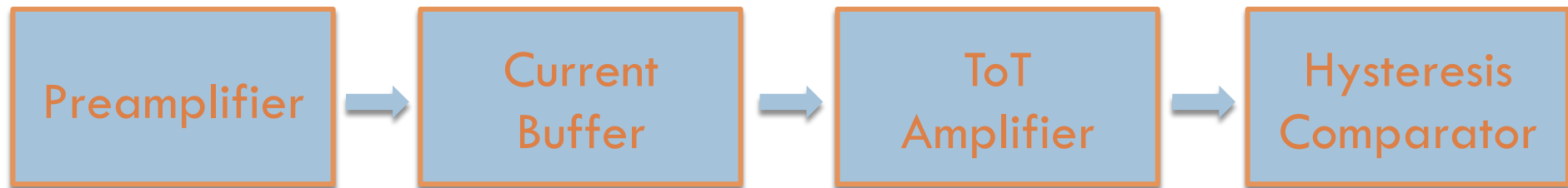
Timing



PASTA Architecture

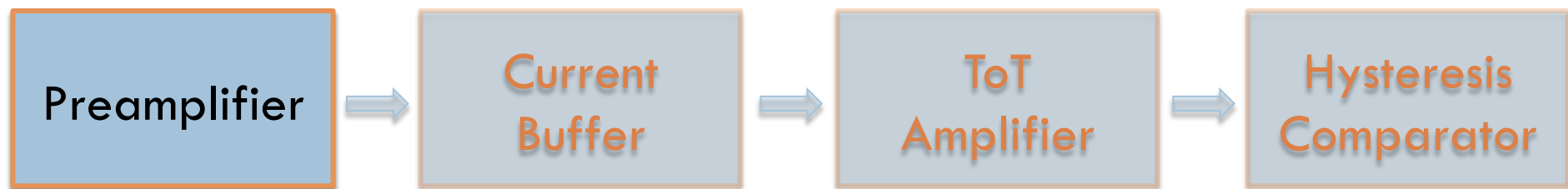


Front-End Implementation



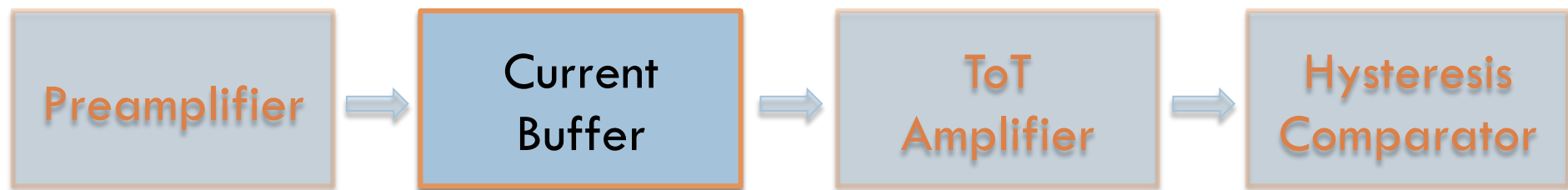
Front-End Implementation

- First preamplification
- Two input polarities, same output polarity



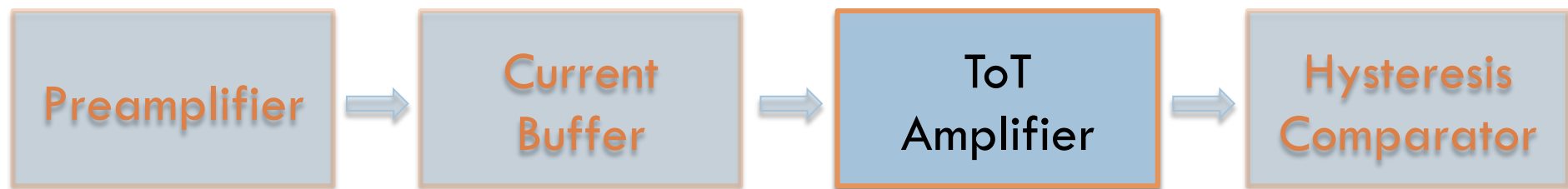
Front-End Implementation

- Current amplification
- Impedance adapter



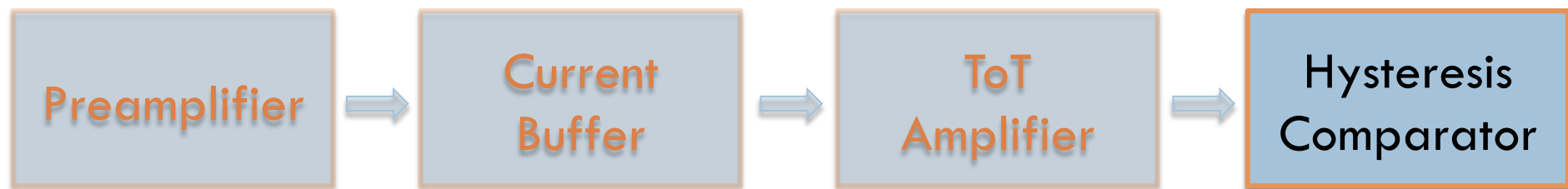
Front-End Implementation

- Last amplification
- Constant current discharge of feedback capacitance

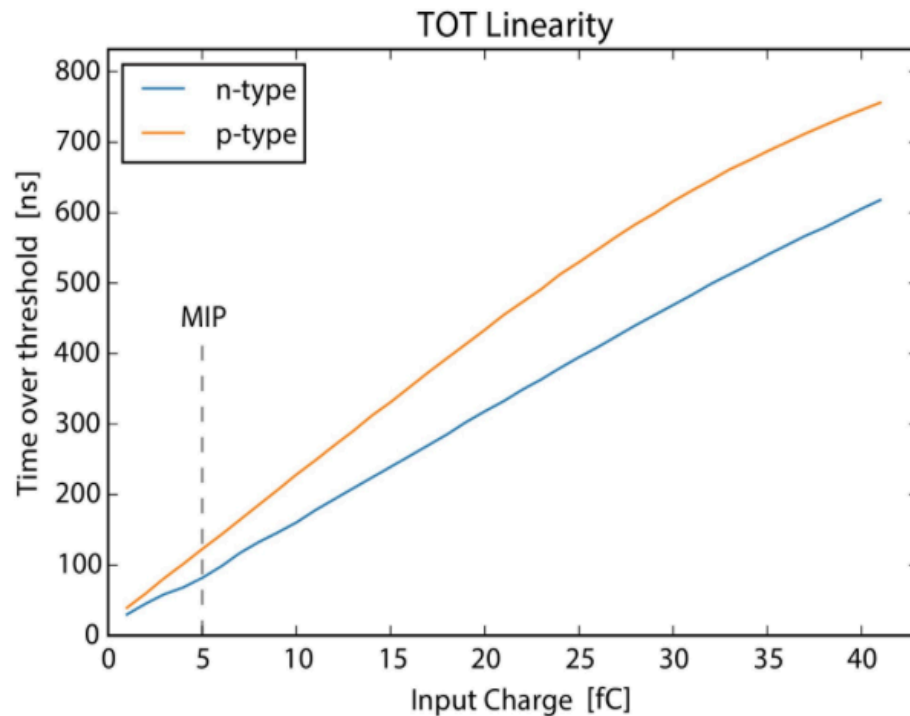


Front-End Implementation

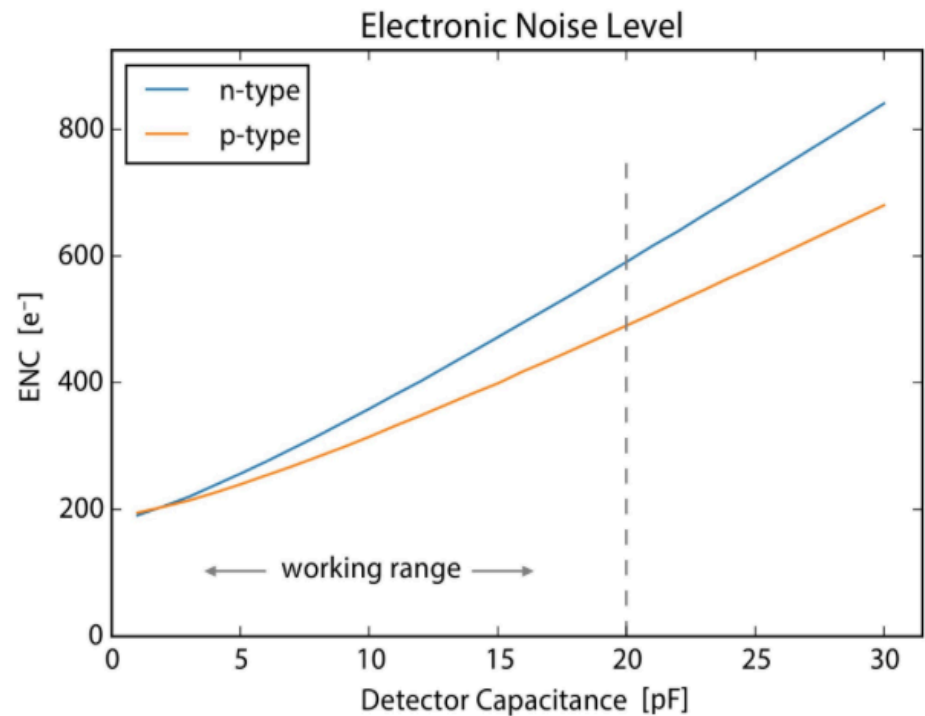
- Low noise sensitivity
- Two for each channel : energy and time branches



Front-End Simulations

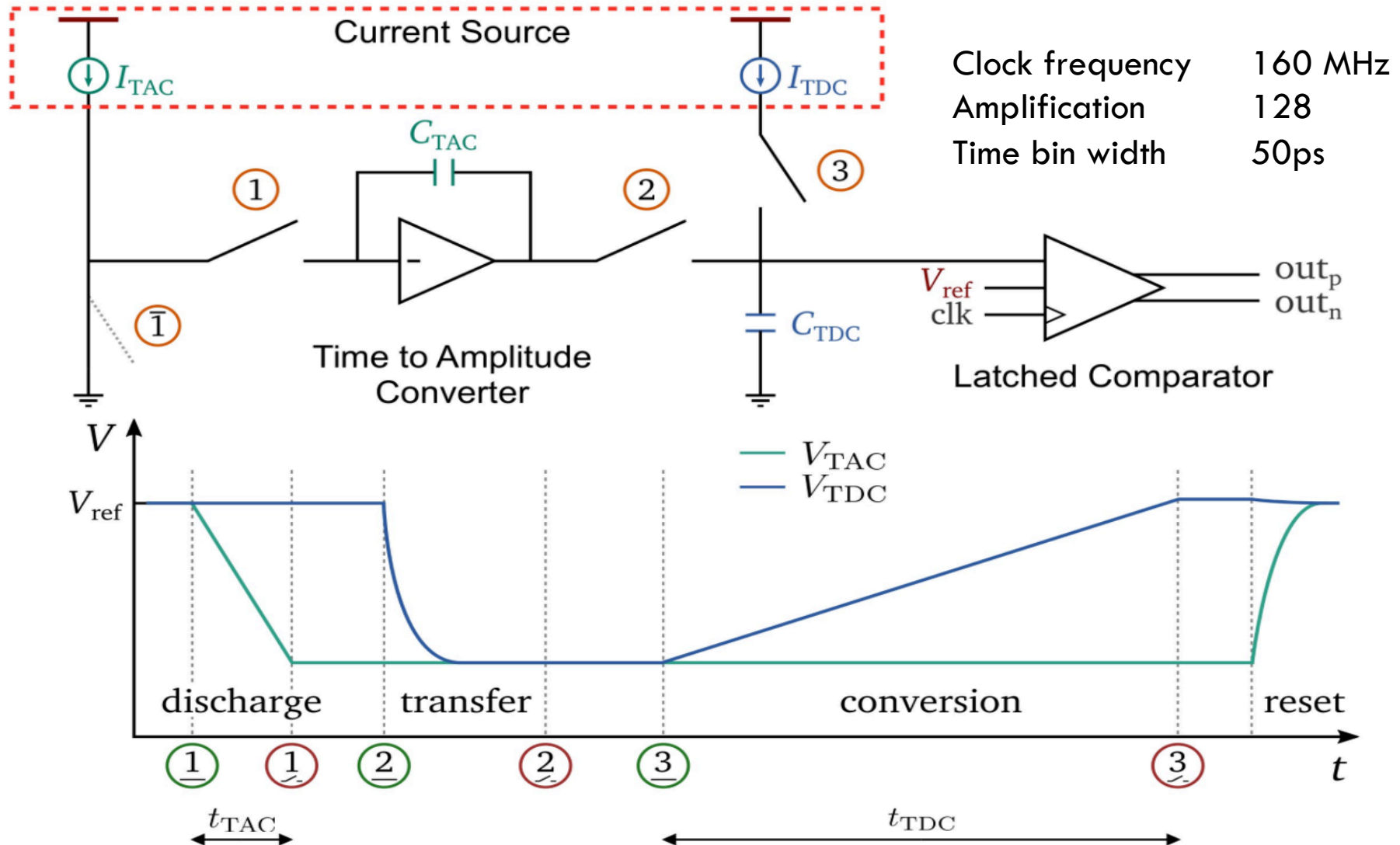


TOT linearity in the input charge range of 1 fC to 40 fC with a capacitance of 25 pF



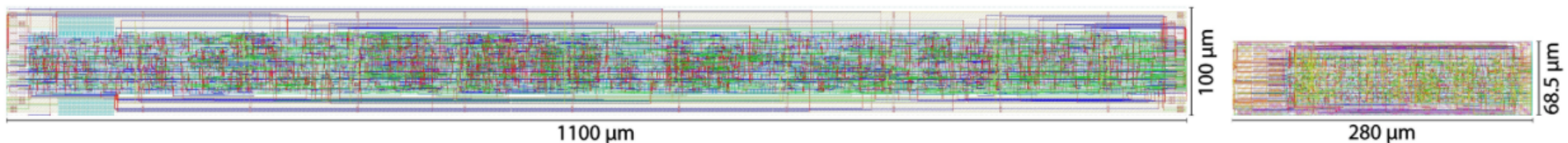
Electronic noise considering an input capacitance in the range 1 pF to 30 pF with an input charge of 4 fC

Analog TDC Performance



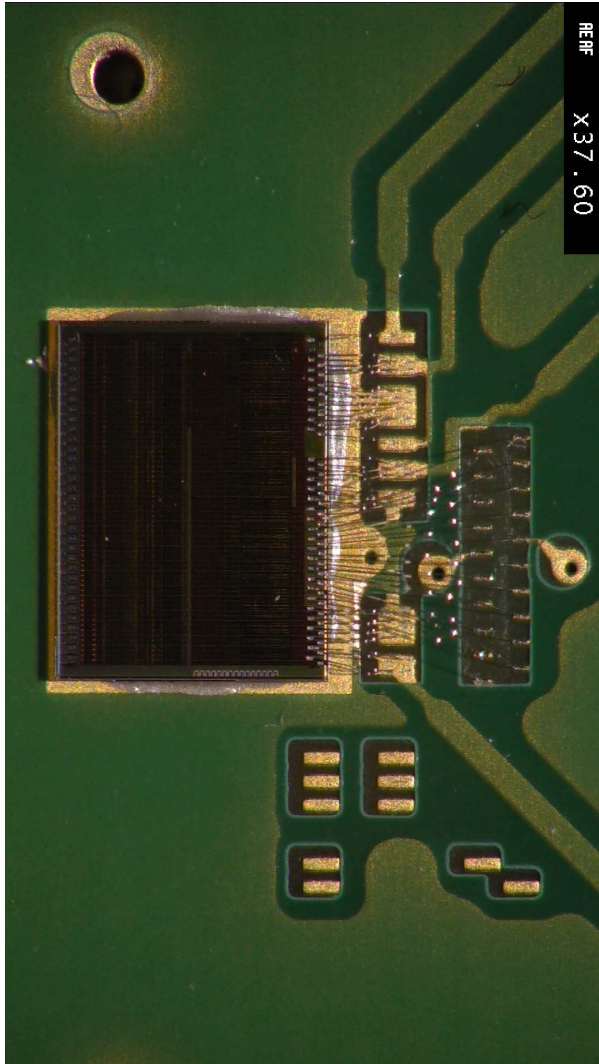
Digital Controllers

- Optimization of the TDC Controller
 - Size reduced by 80%
 - Overall power consumption halved
 - Radiation-hard logic implemented



- Single Event Upset protection
 - 1 bit : Triple Modular redundancy
 - n bits : Hamming encoding

Current Status



- Chip bonded to the power board
- Power supplies tested
- Readout system under test

Outlook



- Board in production
- First tests scheduled
- Beam test with sensor planned in the middle of the year



Alberto Riccardi

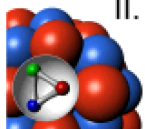
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Thank you for your attention

GEFÖRDERT VOM



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und Forschung



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Institut

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